EPC2037 – Enhancement Mode Power Transistor

 $\overline{V_{DS}}$, $100\,\overline{V}$ $R_{DS(on)}$, $550\,m\Omega$ I_D , $1.7\,A$









Revised August 21, 2024

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low $R_{DS(on)}$, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Application Notes:

- Easy-to-use and reliable gate, Gate Drive ON = 5 V typical, OFF = 0 V (negative voltage not needed)
- Top of FET is electrically connected to source

Questions:	VCK
Ask a GaN	AN EXPERT GaM
Expert	Gan

	Maximum Ratings					
	PARAMETER	VALUE	UNIT			
V	Drain-to-Source Voltage (Continuous)	100				
v _{DS}	V _{DS} Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)		V			
	$I_{D} = \frac{\text{Continuous} (T_{A} = 25^{\circ}\text{C}, R_{\theta JA} = 44^{\circ}\text{C/W})}{\text{Pulsed} (25^{\circ}\text{C}, T_{\text{PULSE}} = 300 \mu\text{s})}$		^			
'D			A			
	Gate-to-Source Voltage	6				
V_{GS}	Gate-to-Source Voltage	-4	V			
	Recommended Gate-to-Source Voltage Operating Range*	4.5 – 5.5				
T _J	Operating Temperature -40 to 150		°C			
T _{STG}	Storage Temperature	-40 to 150				

[&]quot;Operating at less than 4 $\ensuremath{V_{GS}}$ is not recommended.

	Thermal Characteristics				
	PARAMETER TYP UNIT				
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	14			
$R_{\theta JB}$	R _{0JB} Thermal Resistance, Junction-to-Board 79		°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	100			

Note 1: R_{BJA} is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details

Static Characteristics (T_j = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 125 \mu\text{A}$	100			٧
I _{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 80 \text{ V}$		10	100	μΑ
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.1	1	mA
I _{GSS}	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		10	100	μΑ
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 0.08 \text{ mA}$	0.8	1.5	2.5	V
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, I}_{D} = 0.1 \text{ A}$		400	550	mΩ
V_{SD}	Source-Drain Forward Voltage#	$V_{GS} = 0 \text{ V, } I_{S} = 0.5 \text{ A}$		2.5		V

[#] Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.



Die size: 0.9 x 0.9 mm

EPC2037 eGaN® FETs are supplied only in passivated die form with solder bumps.

Applications

- High speed DC-DC conversion
- Wireless power transfer
- Lidar/pulsed power applications
- Class-D audio

Benefits

- · Ultra high efficiency
- Ultra low R_{DS(on)}
- Ultra low Q_G
- · Ultra small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2037

Dynamic Characteristics [#] (T _J = 25°C unless otherwise stated)						
PARAMETER TEST CONDITION		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			14	17	
C _{RSS}	Reverse Transfer Capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 50 \text{ V}$		0.1		
Coss	Output Capacitance			6.5	10	pF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V 0VV 0+- 50V		9.5		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 50 \text{ V}$		12		
R _G	Gate Resistance			0.5		Ω
Q _G	Total Gate Charge	$V_{GS} = 5 \text{ V}, V_{DS} = 50 \text{ V}, I_D = 0.1 \text{ A}$		115	145	
Q _{GS}	Gate-to-Source Charge			32		
Q _{GD}	Gate-to-Drain Charge	$V_{DS} = 50 \text{ V}, I_D = 0.1 \text{ A}$		25		
Q _{G(TH)}	Gate Charge at Threshold	V _{GS} = 0 V, V _{DS} = 50 V 600			pC	
Qoss	Output Charge			900		
Q _{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

All measurements were done with substrate connected to source.

Figure 1: Typical Output Characteristics at 25°C

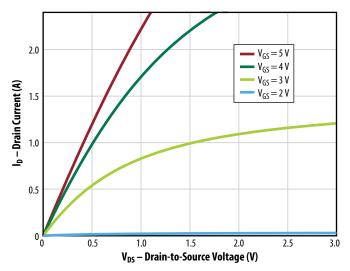


Figure 3: Typical $R_{\text{DS(on)}}\, vs.\, V_{\text{GS}}$ for Various Drain Currents

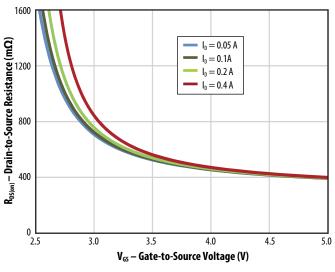


Figure 2: Typical Transfer Characteristics

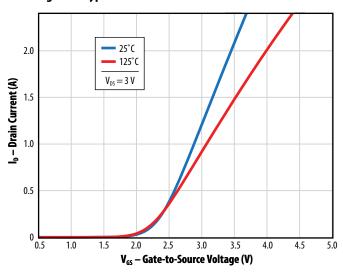
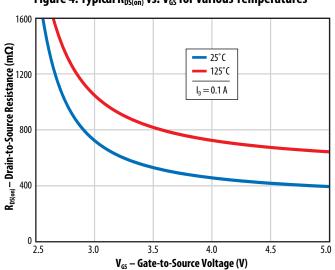


Figure 4: Typical R_{DS(on)} vs. V_{GS} for Various Temperatures



Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}. Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 50% BV_{DSS}.

Figure 5a: Typical Capacitance (Linear Scale)

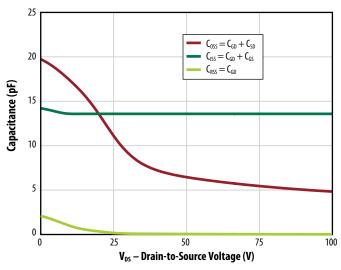


Figure 5b: Typical Capacitance (Log Scale)

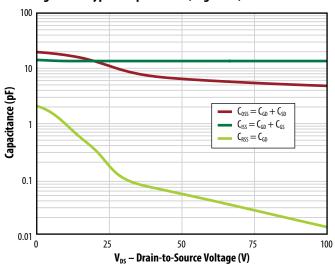


Figure 6: Typical Gate Charge

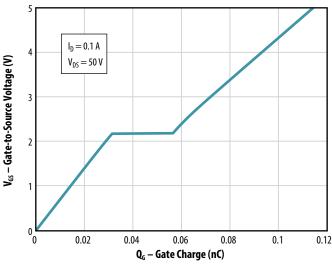
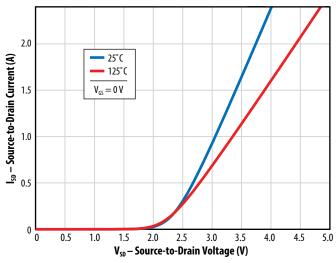


Figure 7: Typical Reverse Drain-Source Characteristics



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 8: Typical Normalized On-State Resistance vs. Temp.

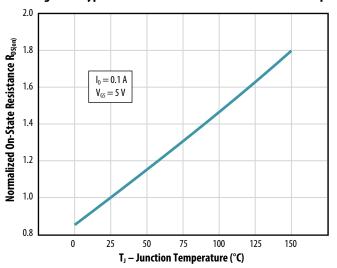
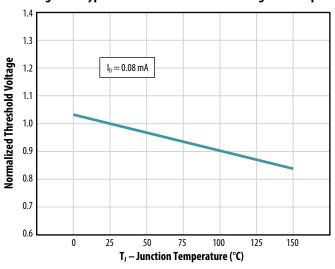


Figure 9: Typical Normalized Threshold Voltage vs. Temp.



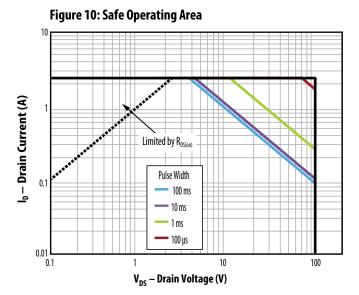
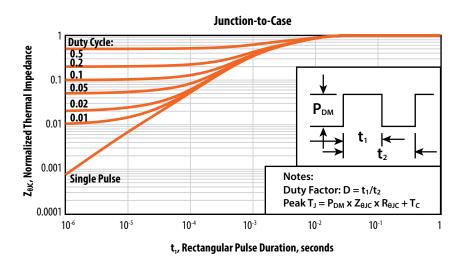
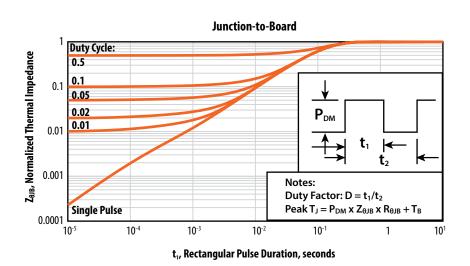


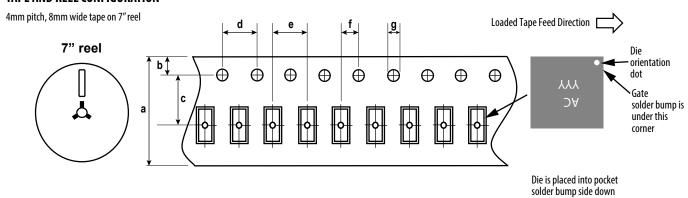
Figure 11: Typical Transient Thermal Response Curves





EPC2037 eGaN® FET DATASHEET

TAPE AND REEL CONFIGURATION

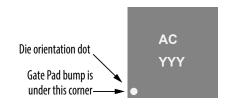


	EPC2037 (note 1)			
Dimension (mm)	target	min	max	
а	8.00	7.90	8.30	
b	1.75	1.65	1.85	
c (see note)	3.50	3.45	3.55	
d	4.00	3.90	4.10	
е	4.00	3.90	4.10	
f (see note)	2.00	1.95	2.05	
g	1.5	1.5	1.6	

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard. Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket,

(face side down)

DIE MARKINGS

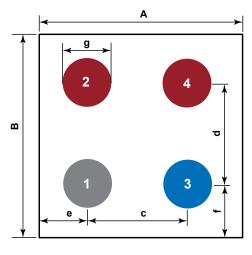


Part	Laser Markings		
Number	Part # Marking Line 1	Lot_Date Code Marking line 2	
EPC2037	AC	YYY	

not the pocket hole.

DIE OUTLINE

Solder Bump View

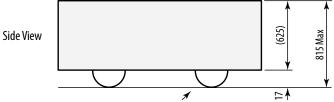


DIM	MIN	Nominal	MAX
Α	870	900	930
В	870	900	930
c	450	450	450
d	450	450	450
e	210	225	240
f	210	225	240
g	187	208	229

Pads 1 is Gate;

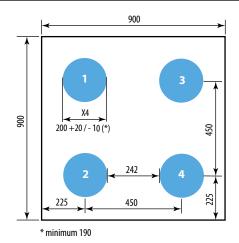
Pad 3 is Drain;

Pads 2, 4 are Source



RECOMMENDED LAND PATTERN

(measurements in µm)



The land pattern is solder mask defined.

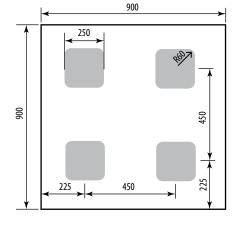
Pads 1 is Gate;

Pad 3 is Drain;

Pads 2, 4 are Source

RECOMMENDED STENCIL DRAWING

(measurements in µm)



Recommended stencil should be 4mil (100 μ m) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/design-support

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EPC Patent Listing: https://epc-co.com/epc/about-epc/patents

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